Semiconductor Memories. Technology, Testing, and Reliability

Description: Semiconductor Memories provides in-depth coverage in the areas of design for testing, fault tolerance, failure modes and mechanisms, and screening and qualification methods including:
- Memory cell structures and fabrication technologies.
- Application-specific memories and architectures.
- Memory design, fault modeling and test algorithms, limitations, and trade-offs.
- Space environment, radiation hardening process and design techniques, and radiation testing.
- Memory stacks and multichip modules for gigabyte storage.

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